

# Long–Memory and Change–Points in Volatility Processes

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# Introduction

- So far we have considered homogeneous long-memory processes, i.e., processes characterized by a single set of parameters,
- This assumption is unrealistic in finance, as financial time series display also (local) trends, changes in regime, etc;
- We then have to consider methods that
  - ① Detect changes in regime for strongly dependent data,
  - ② Provide an unbiased estimate of the memory parameter for non-homogeneous time series.

# The change-point problem

- Consider the realized time series  $\{Y_1, \dots, Y_T\}$ ,
- Is this series characterized by a constant vector parameter  $\theta$
- Or is this vector changing over time?
- For financial time series, the hypothesis of a constant vector parameter is unlikely.
- Change-point detection of a GARCH process allows to estimate the parameters of this process on the largest interval of homogeneity, and then obtain an unbiased estimate of the volatility.
- This is of interest for
  - ① Practitioners using GARCH models for risk management,
  - ② Traders using GARCH models for correcting the bias in the Black-Scholes formula.

# Change-point detection: the FTSE 100 index

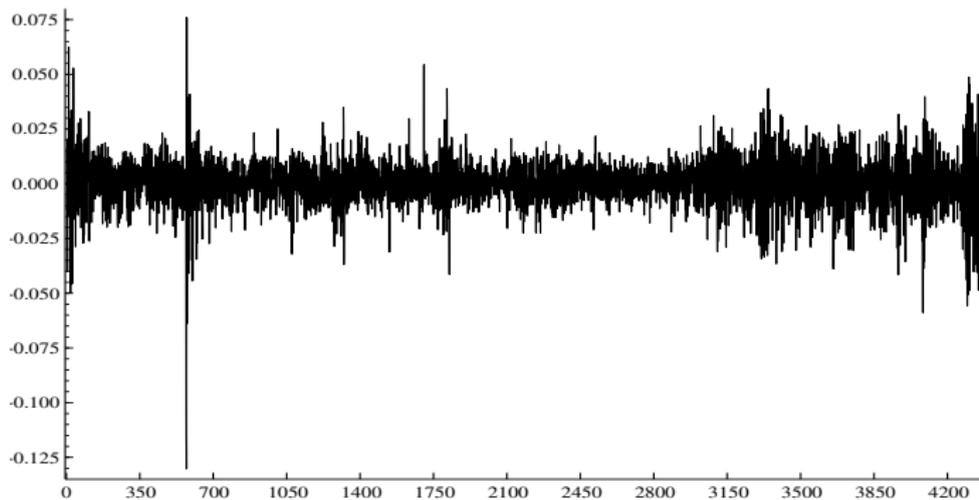


Figure: Returns on the FTSE 100 index  $X_t = \log(P_t/P_{t-1})$  (1986–2002)

We observe intermittency of the volatility process: large variations are followed by variations of smaller magnitude.

# Splitting the series in shorter intervals with homogeneous variance

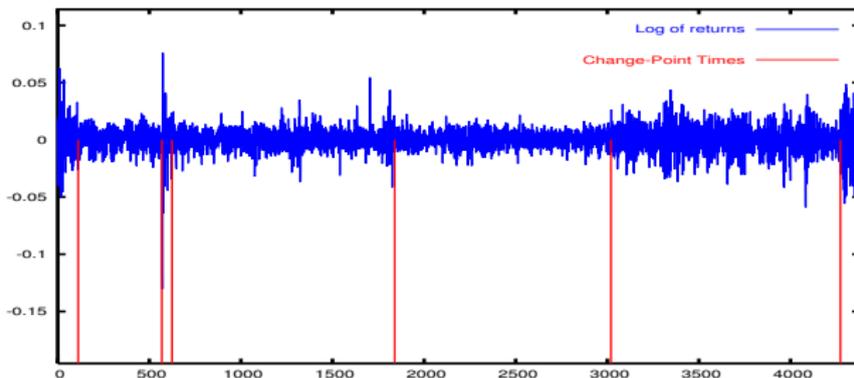


Figure: Returns on the FTSE 100 index  $X_t = \log(P_t/P_{t-1})$  (1986–2002)

## Note

The Gaussian adaptive method used for this splitting will be exposed later.

# Empirical properties of strong dependence in volatility

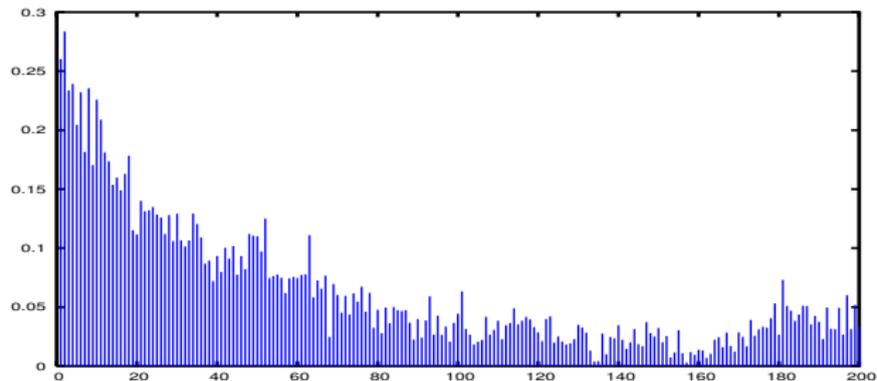


Figure: ACF of  $|X_t|$  over the time interval (1986–2002)

## Remark

*ACF decays hyperbolically to zero, like a long-memory process*

# Characterization of the dependence structure with the ACF

- For a short-range dependent process, the ACF decays quickly to zero, the decay rate is said exponential.

$$\sum_{k=-\infty}^{\infty} |\gamma(k)| < \infty$$

## Example

*AR(1) process  $Y_t = a_1 Y_{t-1} + \varepsilon$ , which has a stationary solution if  $|a_1| < 1$ ,*

$$\gamma(k) = \frac{\sigma^2}{1 - a_1^2} a_1^{|k|}, \quad \sigma^2 = \text{Var}(\varepsilon)$$

- For a second order stationary strongly dependent process, the ACF decays as follows:

$$\gamma(k) \sim k^{2d-1}, \quad d \in (0, 1/2),$$

# Consider the ACF on sub-intervals

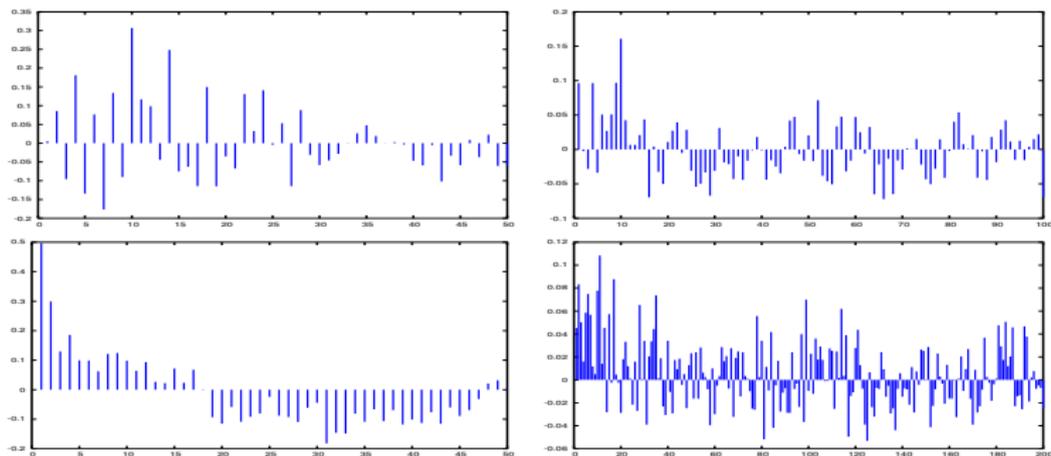


Figure: ACF of  $|X_t|$  over the time intervals :  
a: Top, left:  $[1, 112]$  ; b: Top, right:  $[113, 568]$   
c: Bottom, left:  $[569, 624]$  ; d: Bottom, right:  $[625, 1840]$

# Temporary conclusions

- 1 Financial time series, when considered as the realization of a single homogeneous process, display some characteristics similar to long-memory processes.
- 2 However, when studied over sub-intervals, these properties of strong dependence are less obvious.
- 3 In our particular case, the dependence property was inferred from the asymptotic behavior of the empirical ACF

$$\hat{\rho}_Y(k) = \frac{\hat{\gamma}_Y(k)}{\hat{\gamma}_Y(0)}, \quad \hat{\gamma}_Y(k) = T^{-1} \sum_{t=k+1}^T (y_t - \bar{y})(y_{t-k} - \bar{y}), \quad \hat{\gamma}_Y(0) = \text{Var}(Y).$$

- 4 One could wonder whether these methods are appropriate,
- 5 First, ACF is not much informative if the process is “not very close” to being Gaussian (see Samorodnitsky, 2002) which is the case of financial time series.
- 6 Next, if the process is not second order stationary, the conclusions drawn from the asymptotic behavior of the ACF are wrong.
- 7 Finally, the volatility process could mix long-range dependence and change-points.

# Change-point detection: parametric tests

- Tests based on the assumption that the process that generates the data is characterized by a finite number of parameters.
- We make the assumption that this process is an ARCH-type process
- These tests are based on the comparison of either the residual process of the ARCH (GARCH) process or likelihood of the process on a moving window splitting the observed sample in two.
- These tests have a drawback, as they consider only the case of a single-change point.

# Tests based on the empirical process of squared residuals of ARCH sequences I

- Process ARCH( $p$ ) defined by:

$$X_t = \sigma_t \varepsilon_t, \quad \sigma_t^2 = b_0 + \sum_{j=1}^p b_j X_{t-j}^2, \quad \varepsilon_t \text{ iid}, \quad E \varepsilon_0 = 0, \quad E \varepsilon_0^2 = 1,$$

$b_0 > 0$  and  $b_i \geq 0$ .

- Empirical process of squared residuals  $\hat{\varepsilon}_t^2 = \frac{X_t^2}{\hat{\sigma}_t^2}$

$$\hat{K}_T(s, t) = \frac{1}{\sqrt{T}} \sum_{1 \leq i \leq [Ts]} [\mathbf{I}\{\hat{\varepsilon}_i^2 \leq t\} - F(t)], \quad 0 < s \leq 1.$$

- $F$  repartition function of  $\varepsilon_0^2$

# Tests based on the empirical process of squared residuals of ARCH sequences II

- Tests based on the process:

$$\hat{T}_T(s, t) = \sqrt{T} \cdot \frac{[Ts]}{T} \left( 1 - \frac{[Ts]}{T} \right) \left( \hat{F}_{[Ts]}(t) - \hat{F}_{T-[Ts]}^*(t) \right),$$

with

$$\hat{F}_{[Ts]}(t) = \frac{1}{[Ts]} \sum_{1 \leq i \leq [Ts]} \mathbf{1}_{\{\hat{\varepsilon}_i^2 \leq t\}}$$

$F_{T-[Ts]}^*(t)$  is analogously defined using indices greater than  $[Ts]$ .

- The test compares the empirical distribution function of  $\hat{\varepsilon}_1^2, \dots, \hat{\varepsilon}_{[Ts]}^2$  with the one of  $\hat{\varepsilon}_{[Ts]+1}^2, \dots, \hat{\varepsilon}_T^2$
- $\hat{T}_T(s, t)$  has the same limit as  $\hat{K}_T(s, t) - \frac{[Ts]}{T} \hat{K}_T(1, t)$

# Tests based on the empirical process of squared residuals of ARCH sequences III

## Assumptions

- 1 Distribution function  $F$  of  $\varepsilon_0^2$  has a derivative  $f(t) = F'(t)$  continuous over  $(0, \infty)$ ,
- 2  $\lim_{t \rightarrow 0} tf(t) = 0$  and  $\lim_{t \rightarrow \infty} tf(t) = 0$ ,
- 3 The vector of parameters  $b$  is estimated by a unbiased estimator  $\hat{b} = (\hat{b}_0, \dots, \hat{b}_p)$  which admits the representation:

$$\hat{b}_i - b_i = \frac{1}{n} \sum_{1 \leq j \leq n} l_i(\varepsilon_j^2) f_i(\varepsilon_{j-1}, \varepsilon_{j-2}, \dots) + o_P(T^{-1/2}), \quad 0 \leq i \leq p,$$

(The PML estimator satisfies this hypothesis.)

- 4 The functions  $l_i$  are regular in the following sense

$$E l_i(\varepsilon_0^2) = 0, \quad E [l_i(\varepsilon_0^2)]^2 < \infty, \quad E [f_i(\varepsilon_0, \varepsilon_{-1}, \dots)]^2 < \infty, \quad 0 \leq i \leq p,$$

- 5  $E \varepsilon_0^4 < \infty$ ,
- 6  $(E \varepsilon_0^4)^{1/2} \sum_{1 \leq j \leq p} b_j < 1$ .

# Tests based on the empirical process of squared residuals of ARCH sequences IV

- Under the previous hypotheses, the asymptotic distribution of the empirical process of the squared residuals of an ARCH sequence is

$$\hat{K}_T(s, t) \xrightarrow{d} K(s, t) + stf(t)\xi,$$

$f$  is the density of  $\varepsilon_i^2$ ,  $\xi$  is a Gaussian VA correlated with  $K(s, t)$ .

- Since

$$\hat{K}_T(s, t) \xrightarrow{d} K(s, t) + stf(t)\xi,$$

then

$$\begin{aligned}\hat{T}_T(s, t) &= \hat{K}_T(s, t) - \frac{[Ts]}{T} \hat{K}_T(1, t) \\ &\sim (K(s, t) + stf(t)\xi) - s(K_T(1, t) + tf(t)\xi) \\ &= K(s, t) - sK(1, t),\end{aligned}$$

# Tests based on the empirical process I

## Kolmogorov-Smirnov test

- For  $1 \leq k \leq T$  define (change-point date  $k$  is unknown)

$$\hat{F}_k(t) = \frac{1}{k} \#\{i \leq k : \hat{\varepsilon}_i^2 \leq t\}, \quad \hat{F}_k^*(t) = \frac{1}{T-k} \#\{i > k : \hat{\varepsilon}_i^2 \leq t\},$$

$$\hat{T}_T(k, t) = \sqrt{T} \cdot \frac{k}{T} \left(1 - \frac{k}{T}\right) \left| \hat{F}_k(t) - \hat{F}_k^*(t) \right|;$$

$$\hat{M}_T = \sup_{0 \leq t \leq \infty} \max_{1 \leq k \leq T} |\hat{T}_T(k, t)| = \max_{1 \leq k \leq T} \max_{1 \leq j \leq T} |\hat{T}_T(k, \hat{\varepsilon}_j^2)|.$$

- The asymptotic distribution of  $\hat{M}_T$  is the same as the generalized Kolmogorov-Smirnov statistic.

# Tests based on the empirical process II

Kolmogorov-Smirnov test

## Remark

*Estimator of the change-point date, (supposed unique):*

$$\hat{k}_M = \max \left\{ k : \max_{1 \leq k \leq T} \max_{1 \leq j \leq T} | \hat{T}_T(k, \hat{\varepsilon}_j^2) | \right\} \quad \text{if} \quad \max_{1 \leq k \leq T} \max_{1 \leq j \leq T} | \hat{T}_T(k, \hat{\varepsilon}_j^2) | \geq \hat{c}_T(\alpha),$$

$\hat{c}_T(\alpha)$ : *asymptotic or bootstrap critical value at the level  $\alpha$*

# Tests based on the empirical process

## Cramér–Von Mises test

- The Cramér – von Mises statistic is defined as:

$$\hat{B} := \int_0^1 \left\{ \frac{1}{T} \sum_{i=1}^T [\hat{\mathcal{K}}([Ts], \hat{\varepsilon}_i^2)]^2 \right\} ds$$

which has approximatively the following asymptotic distribution:

$$\hat{B} \sim B := \int_0^1 \int_0^1 \mathcal{K}^2(s, u) duds,$$

where  $\mathcal{K}$  is the Kiefer process.

- Critical values are obtained from Blum, Kiefer and Rosenblatt (1961).

# Tests based on the generalized likelihood ratio I

- We consider as null hypothesis a GARCH(1,1) model with constants coefficients:

$$X_t = \sigma_t \varepsilon_t, \quad \varepsilon_t \sim N(0, \sigma_t^2), \quad \sigma_t^2 = \omega + \beta \sigma_{t-1}^2 + \alpha \varepsilon_{t-1}^2,$$

- Under the alternative hypothesis, for  $t > t_0$ , the process is defined as:

$$X_t = \sigma_t \varepsilon_t, \quad \varepsilon_t \sim N(0, \sigma_t^2), \quad \sigma_t^2 = \omega^* + \beta^* \sigma_{t-1}^2 + \alpha^* \varepsilon_{t-1}^2,$$

where  $\omega^* \neq \omega$ , or  $\beta^* \neq \beta$ , or  $\alpha^* \neq \alpha$ .

## Definition

*The generalized likelihood ratio statistic is defined as:*

$$\Lambda_{t_0} = \frac{\text{maximum of the likelihood function under the null hypothesis}}{\text{maximum of the likelihood function if change-point in } t_0}.$$

see Csörgő and Horváth (1997)

# Tests based on the generalized likelihood ratio II

## Notations

- $\hat{\omega}, \hat{\alpha}, \hat{\beta}$ : estimated values from the whole sample  $X_1, \dots, X_T$ ,
- $\tilde{\omega}, \tilde{\alpha}, \tilde{\beta}$ : estimated values from the sub-sample  $X_1, \dots, X_{t_0}$ ,
- $\bar{\omega}, \bar{\alpha}, \bar{\beta}$ : estimated values from the sub-sample  $X_{t_0+1}, \dots, X_T$ .
- Define  $\hat{\sigma}_t^2 = \hat{\omega} + \hat{\beta}\hat{\sigma}_{t-1}^2 + \hat{\alpha}\hat{\varepsilon}_{t-1}^2$ ,
- Define  $(\bar{\sigma}_t^2, \tilde{\sigma}_t^2)$  similarly as  $\hat{\sigma}_t^2$ .

Since the likelihood is Gaussian

$$\begin{aligned} -2 \ln \Lambda_{t_0} = & - \left[ \sum_{t=1}^{t_0} (\ln \tilde{\sigma}_t^2 - \ln \hat{\sigma}_t^2) + \sum_{t=t_0+1}^T (\ln \bar{\sigma}_t^2 - \ln \hat{\sigma}_t^2) \right] \\ & + \sum_{t=1}^n \frac{\hat{\varepsilon}_t^2}{\hat{\sigma}_t^2} - \sum_{t=1}^{t_0} \frac{\hat{\varepsilon}_t^2}{\tilde{\sigma}_t^2} - \sum_{t=t_0+1}^T \frac{\hat{\varepsilon}_t^2}{\bar{\sigma}_t^2} \end{aligned}$$

# Tests based on the generalized likelihood ratio III

- Since the change-point date  $t_0$  is unknown, we consider the statistic:

$$\Lambda_T^* = \max_{1 \leq k \leq T} -2 \ln \Lambda_k$$

- Even if observations are iid, the statistic  $\Lambda_T^*$  satisfies an Erdős-type limit theorem, with an exponential distribution as limit.
- The critical value, over which  $H_0$  is rejected, is:

$$c_T(\alpha) = \frac{[D_d(\log T) - \log[-\log(1 - \alpha)] + \log 2]^2}{2 \log \log T},$$

$$\text{with } D_d(x) = 2 \log x + \frac{d}{2} \log \log x - \log \Gamma\left(\frac{d}{2}\right).$$

## Remark

*The convergence rate of this limit is very slow, and asymptotic critical values are far greater than the ones obtained in small sample by simulation, see Gombay and Horváth (1996).*

# Tests based on the generalized likelihood ratio IV

- The generalized likelihood ratio statistic is based on the process

$$\{h(1-h)(-2 \ln \Lambda_{[Th]}), 0 < h < 1\}$$

- If observations are independent, with a density depending on  $b$  parameters, then this process can be approximated by

$$\left\{ \sum_{i=1}^b (W_i^0)^2(h), 0 < h < 1 \right\}$$

where  $W_i^0(\cdot), i = 1, \dots, b$  are independent Brownian bridges on  $[0, 1]$ .

- Under the null hypothesis of constancy of parameters

$$\Delta_T^* := T^{-3} \sum_{k=1}^{T-1} k(T-k)(-2 \ln \Lambda_k) \xrightarrow{d} \int_0^1 \sum_{i=1}^b (W_i^0)^2(h) dh.$$

- Critical values for  $\Delta_T^*$  are obtained from Kiefer (1959).

# Test by Inlan and Tiao (1994)

- Based on the process  $\{D_T(h), h \in [0, 1]\}$

$$D_T(h) := \frac{\sum_{j=1}^{\lceil Th \rceil} X_j^2}{\sum_{j=1}^T X_j^2} - \frac{\lceil Th \rceil}{T}, \quad h \in [0, 1].$$

- Under the null hypothesis  $H_0$  of constant variance, the process  $\{D_T(h), h \in [0, 1]\}$  converges to a Brownian bridge over  $[0, 1]$ .
- A test of constancy of the unconditional variance is based on the following functional of the process  $\{D_T(h)\}$ , which under  $H_0$  converges to the supremum of a Brownian bridge over  $[0, 1]$ .

$$\sqrt{T/2} \sup_{0 \leq h \leq 1} |D_T(h)| \xrightarrow{d} \sup_{0 \leq h \leq 1} |W^0(h)|.$$

# CUSUM test by Kokoszka and Leipus (1999) I

- We make the assumption that  $\{X_t\}$  is an ARCH( $\infty$ ) process defined by:

$$X_t = \sigma_t \varepsilon_t, \quad \varepsilon_t \sim \text{iid}, \quad E\varepsilon_0 = 0, \quad \text{Var} \varepsilon_0 = 1,$$

$$\sigma_t^2 = \omega + \sum_{j=1}^{\infty} \alpha_j X_{t-j}^2, \quad t = 1, \dots, t_0,$$

$$\sigma_t^2 = \omega^* + \sum_{j=1}^{\infty} \alpha_j^* X_{t-j}^2, \quad t = t_0 + 1, \dots, T,$$

and we make the additional assumption that the unconditional variance changes at time  $t_0$ , supposed unknown:

$$\Delta(n) = \frac{\omega}{1 - \sum_{j=1}^{\infty} \alpha_j} - \frac{\omega^*}{1 - \sum_{j=1}^{\infty} \alpha_j^*} \neq 0.$$

- The null hypothesis is  $H_0 : \omega = \omega^*, \alpha_j = \alpha_j^*$  for all  $j$ , while the alternative hypothesis is that there exists  $j$  such that  $H_A : \omega \neq \omega^*$  or  $\alpha_j \neq \alpha_j^*$ .

# CUSUM test by Kokoszka and Leipus (1999) II

- The CUSUM test is based on the process  $\{U_T(h), h \in [0, 1]\}$  defined by:

$$U_T(h) := \sqrt{T} \frac{[Th](T - [Th])}{T^2} \left( \frac{1}{[Th]} \sum_{j=1}^{[Th]} X_j^2 - \frac{1}{T - [Th]} \sum_{j=[Th]+1}^T X_j^2 \right),$$

- The test statistic is based on the following functional of the process  $\{U_T(h), h \in [0, 1]\}$

$$\sup_{0 \leq h \leq 1} |U_T(h)| / \sigma \xrightarrow{d} \sup_{0 \leq h \leq 1} |W^0(h)|,$$

- The variance  $\sigma^2$  is usually estimated by spectral methods, i.e., we use the non-parametric estimator  $s_T^2(q)$ .

# The binary segmentation algorithm

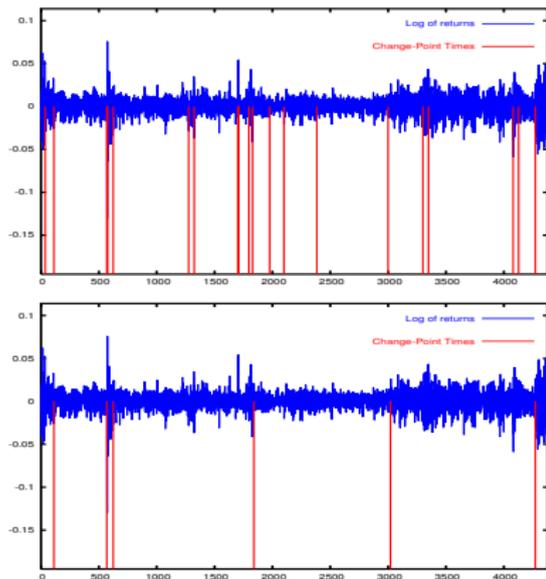
Algorithm proposed by Vostrikova (1981), which allows to extend single change-point methods to the multiple change-point case

## Algorithm

- 1 Apply the single change-point procedure on the whole sample
- 2 If a change-point is detected, divide the sample in two at the estimated change-point date,
- 3 Apply the single change-point procedure on these two subsamples,
- 4 Apply iteratively the procedure until no further change-point is found on the new segments.

# Drawbacks of the local method

- Top : Binary segmentation procedure
- Bottom : Adaptive method



## Open question

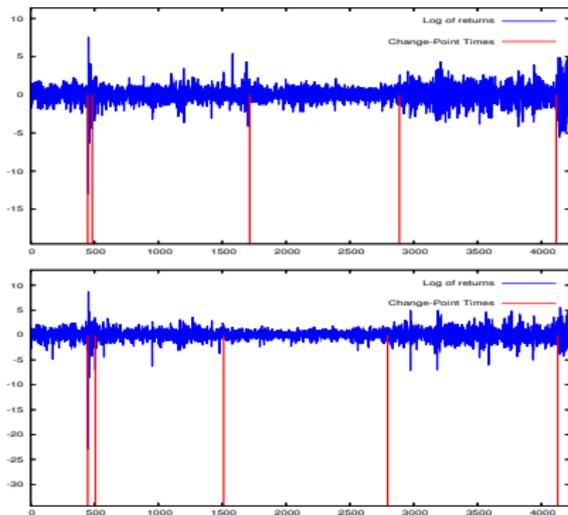
Which segmentation (dimension of the model) is the right one?

Global method has some interesting properties:

- ① This method can detect several change-points at unknown dates,
- ② Even if the data are strongly dependent,
- ③ This method is based on a Gaussian likelihood, and then can be adapted to the multivariate case,
- ④ This multivariate case is relevant if the series have common change-point times,
- ⑤ Finally, even if the data are non Gaussian, this methods works practically well, (interesting results on financial data)

# Relevance of the global method

An empirical example: the FTSE 100 and S&P 500 over the time interval 1986–2002



- Adaptive detection of multiple change-point in the univariate case:
- Top: returns on the FTSE 100 index,
- Bottom: returns on the S&P 500 index,
- (The estimated change-point times are represented by vertical lines)

## Remark

*Change-point times for both series look common.*

# The global method

- We assume that the  $m$ -dimensional process  $\{\mathbf{Y}_t = (Y_{1,t}, \dots, Y_{m,t})'\}$  abruptly changes and is characterized by a (vector) parameter  $\theta \in \Theta$ , which is constant between two changes.
- Let  $K$  be an integer and let  $\tau = \{\tau_1, \tau_2, \dots, \tau_{K-1}\}$  be an ordered sequence of integers that verify  $0 < \tau_1 < \tau_2 < \dots < \tau_{K-1} < T$ .
- For all  $1 \leq k \leq K$ , let  $U(\mathbf{Y}_{\tau_{k-1}+1}, \dots, \mathbf{Y}_{\tau_k}; \theta)$  be a contrast function used for estimating the true value of the parameter over the segment  $k$ .
- The minimum contrast estimator (MCE) of  $\hat{\theta}(\mathbf{Y}_{\tau_{k-1}+1}, \dots, \mathbf{Y}_{\tau_k})$ , evaluated over the  $k^{\text{th}}$  segment of  $\tau$ , is defined as the solution of the following minimization problem:

$$U\left(\mathbf{Y}_{\tau_{k-1}+1}, \dots, \mathbf{Y}_{\tau_k}; \hat{\theta}(\mathbf{Y}_{\tau_{k-1}+1}, \dots, \mathbf{Y}_{\tau_k})\right) \leq U(\mathbf{Y}_{\tau_{k-1}+1}, \dots, \mathbf{Y}_{\tau_k}; \theta), \forall \theta \in \Theta.$$

# The global method: contrast function I

- For all  $1 \leq k \leq K$ , define  $G$  as follows:

$$G(\mathbf{Y}_{\tau_{k-1}+1}, \dots, \mathbf{Y}_{\tau_k}) = U\left(\mathbf{Y}_{\tau_{k-1}+1}, \dots, \mathbf{Y}_{\tau_k}; \hat{\theta}(\mathbf{Y}_{\tau_{k-1}+1}, \dots, \mathbf{Y}_{\tau_k})\right).$$

- We define the contrast function as  $J(\boldsymbol{\tau}, \mathbf{Y})$  :

$$J(\boldsymbol{\tau}, \mathbf{Y}) = \frac{1}{T} \sum_{k=1}^K G(\mathbf{Y}_{\tau_{k-1}+1}, \dots, \mathbf{Y}_{\tau_k}),$$

with  $\tau_0 = 0$  and  $\tau_K = T$ .

# The global method: contrast function II

- We consider the general case of change-point in the covariance matrix of the series  $\{\mathbf{Y}_t\}$ ,
- More precisely, we assume that there exists an integer  $K^*$ , a sequence  $\tau^* = \{\tau_1^*, \tau_2^*, \dots, \tau_{K^*}^*\}$  with  $\tau_0^* = 0 < \tau_1^* < \dots < \tau_{K^*-1}^* < \tau_{K^*}^* = T$  and  $K^*$  ( $m \times m$ ) covariance matrices  $\boldsymbol{\Sigma}_1, \boldsymbol{\Sigma}_2, \dots, \boldsymbol{\Sigma}_{K^*}$  such that  $\text{Cov} \mathbf{Y}_t = \mathbb{E}(\mathbf{Y}_t - \mathbb{E}(\mathbf{Y}_t))(\mathbf{Y}_t - \mathbb{E}(\mathbf{Y}_t))' = \boldsymbol{\Sigma}_k$  for  $\tau_{k-1}^* + 1 \leq t \leq \tau_k^*$ .
- We consider two particular configurations:

# The global method: contrast function III

**Model M1:** There exists an  $m$ -dimensional vector  $\mu$  such that  $\mathbb{E}(\mathbf{Y}_t) = \mu$  for  $t = 1, 2, \dots, T$ . Further,  $\Sigma_k \neq \Sigma_{k+1}$  for  $1 \leq k \leq K^* - 1$ .

In the simplest case of change-points in the covariance matrix, without change in the mean, which is of interest for multivariate volatility processes, we use the following contrast function based on the Gaussian log-likelihood function:

$$J(\tau, \mathbf{Y}) = \frac{1}{T} \sum_{k=1}^K n_k \log |\widehat{\Sigma}_{\tau_k}|, \quad (C_1)$$

where  $n_k = \tau_k - \tau_{k-1}$  is the length of the segment  $k$ ,  $\widehat{\Sigma}_{\tau_k}$  is the  $(m \times m)$  covariance matrix evaluated on the segment  $k$ :

$$\widehat{\Sigma}_{\tau_k} = \frac{1}{n_k} \sum_{t=\tau_{k-1}+1}^{\tau_k} (\mathbf{Y}_t - \bar{\mathbf{Y}})(\mathbf{Y}_t - \bar{\mathbf{Y}})'$$

$\bar{\mathbf{Y}} = T^{-1} \sum_{t=1}^T \mathbf{Y}_t$  : sample mean of the  $m$ -dimensional vector  $\mathbf{Y}_t$  evaluated on the whole sample.

# The global method: contrast function IV

**Model M2:** There exists  $K^*$   $m$ -dimensional vectors  $\mu_1, \dots, \mu_{K^*}$  such that  $\mathbb{E}(\mathbf{Y}_t) = \mu_k$  for  $\tau_{k-1}^* + 1 \leq t \leq \tau_k^*$ . Furthermore,  $(\mu_k, \boldsymbol{\Sigma}_k) \neq (\mu_{k+1}, \boldsymbol{\Sigma}_{k+1})$  for  $1 \leq k \leq K^* - 1$ .

For the detection of change-points in the vector of mean and/or covariance matrix of a multivariate sequence of random variables, the contrast function reduces to;

$$J(\boldsymbol{\tau}, \mathbf{Y}) = \frac{1}{T} \sum_{k=1}^K n_k \log |\widehat{\boldsymbol{\Sigma}}_{\tau_k}| \quad (\text{C}_2)$$

where the covariance matrix  $\widehat{\boldsymbol{\Sigma}}_{\tau_k}$  of dimension  $(m \times m)$  is evaluated over the segment  $k$  :

$$\widehat{\boldsymbol{\Sigma}}_{\tau_k} = \frac{1}{n_k} \sum_{t=\tau_{k-1}+1}^{\tau_k} (\mathbf{Y}_t - \bar{\mathbf{Y}}_{\tau_k})(\mathbf{Y}_t - \bar{\mathbf{Y}}_{\tau_k})'$$

$\bar{\mathbf{Y}}_{\tau_k} = n_k^{-1} \sum_{t=\tau_{k-1}+1}^{\tau_k} \mathbf{Y}_t$  : sample mean of the  $m$ -dimensional vector  $\mathbf{Y}_t$  over that segment.

# The global method: contrast function $V$

Asymptotic results for the minimum contrast estimator of  $\tau^*$  are obtained in the following framework:

- **A1** For all  $1 \leq i \leq m$  and all  $1 \leq t \leq T$ , define  $\eta_{t,i} = Y_{t,i} - \mathbb{E}(Y_{t,i})$ . There exists  $C > 0$  and  $1 \leq h < 2$  such that for all  $u \geq 0$  and all  $s \geq 1$ ,

$$\mathbb{E} \left( \sum_{t=u+1}^{u+s} \eta_{t,i} \right)^2 \leq C(\theta) s^h.$$

(**A1** is verified for  $h = 1$  for both weakly dependent processes and  $1 < h < 2$  for strongly dependent processes.)

- **A2** There exists a sequence  $0 < a_1 < a_2 < \dots < a_{K^*-1} < a_{K^*} = 1$  such that for all  $T \geq 1$  and for all  $1 \leq k \leq K^* - 1$ ,  $\tau_k^* = [Ta_k]$ .

# The global method: contrast function VI

When the real number of segments  $K^*$  is known, we have the following result on the convergence rate of the MCE of  $\tau^*$ :

## Theorem

Suppose that **A1-A2** are verified. In the case **M1** (resp. **M2**), let  $\hat{\tau}_T$  be the dates that minimize the empirical contrast  $J(\tau, \mathbf{Y})$  defined by equation (C<sub>1</sub>) (resp. (C<sub>2</sub>)). Then, the sequence  $\{T \|\hat{\tau}_T - \tau^*\|_\infty\}$  is uniformly tight in probability:

$$\lim_{T \rightarrow \infty} \lim_{\delta \rightarrow \infty} \mathbb{P} \left( \max_{1 \leq k \leq K^* - 1} |\hat{\tau}_{T,k} - \tau_k^*| > \delta \right) = 0. \quad (C_3)$$

(Here,  $J(\tau, \mathbf{Y})$  is minimized over all possible sequences  $\tau$  with length  $K^*$ )

# The global method: contrast function VII

We use a Gaussian contrast function:

- Univariate case:  $J(\boldsymbol{\tau}, \mathbf{Y}) = \frac{1}{T} \sum_{k=1}^K T_k \log \sigma_k^2$ ,  $\boldsymbol{\tau} = \{\tau_1, \tau_2, \dots, \tau_{K-1}\}$  is an ordered sequence of integers satisfying  $0 < \tau_1 < \tau_2 < \dots < \tau_{K-1} < T$ ,  $n_k = \tau_k - \tau_{k-1}$  is the length of the segment  $k$ ,
- Multivariate case:  $J(\boldsymbol{\tau}, \mathbf{Y}) = \frac{1}{T} \sum_{k=1}^K T_k \log |\hat{\boldsymbol{\Sigma}}_{\tau_k}|$

The  $(m \times m)$  empirical covariance matrix  $\hat{\boldsymbol{\Sigma}}_{\tau_k}$  is evaluated over the segment  $k$

$$\hat{\boldsymbol{\Sigma}}_{\tau_k} = \frac{1}{n_k} \sum_{t=\tau_{k-1}+1}^{\tau_k} (\mathbf{Y}_t - \bar{\mathbf{Y}}_{\tau_k})(\mathbf{Y}_t - \bar{\mathbf{Y}}_{\tau_k})'$$

$\bar{\mathbf{Y}}_{\tau_k} = T_k^{-1} \sum_{t=\tau_{k-1}+1}^{\tau_k} \mathbf{Y}_t$  : sample mean of the  $m$ -dimensional vector  $\mathbf{Y}_t$  over that segment.

# The global method: contrast function VIII

Change-point times are estimated by minimizing the penalized contrast function

$$J(\boldsymbol{\tau}, \mathbf{y}) + \beta \text{pen}(\boldsymbol{\tau}) = J(\boldsymbol{\tau}, \mathbf{y}) + \beta_T K$$

where

- 1  $\beta_T K$  : penalty term that controls the level of resolution of the segmentation  
 $\boldsymbol{\tau} = \{\tau_1, \tau_2, \dots, \tau_{K-1}\}$ .
- 2 If  $\beta$  is a function of  $T$  that tends to 0 when  $T$  tends to  $\infty$ , the following theorem states that the number of estimated segments converges in probability to  $K^*$ .

# Penalty term I

## Theorem

Let  $\{\beta_T\}$  be a sequence of positive real numbers such that

$$\beta_T \xrightarrow{T \rightarrow \infty} 0 \text{ and } T^{2-h} \beta_T \xrightarrow{T \rightarrow \infty} \infty, \quad 1 \leq h < 2.$$

Then, under the hypotheses **A1-A2**, the estimated number of segments  $K(\hat{\tau}_T)$ , where  $\hat{\tau}_T$  is the penalized MCE estimator of  $\tau^*$ , i.e., obtained by minimizing  $J(\tau, \mathbf{Y}) + \beta_T \text{pen}(\tau)$ , converges in probability to  $K^*$ .

## Remark

The contrast function  $J(\tau, \mathbf{Y})$  is minimized over the set of all possible sequences  $\tau$  and for all possible  $K$ ,  $1 \leq K \leq K_{\max}$ ,  $K_{\max}$  is a finite upper bound of  $K^*$

# Penalty term II

Standard choice for  $\beta$  (that overestimate the number of change-points)

- $\beta_T = \log(T)/T$  (BIC)
- $\beta_T = 4 \log(T)/T^{1-2d}$  for strongly dependent series.
- The parameter  $d$  is unknown,
- How to estimate  $d$  from the data?
- If the process is not stationary, standard estimation method seen in the previous lectures provide incorrect results that overestimate the parameter  $d$  and artificially increase  $\beta$ .
- We can use methods robust to nonstationarity, like wavelets methods based on the scaling properties of the wavelets coefficients, but these methods require a large sample size.
- We then resort to adaptive methods, i.e., methods such that the segmentation does not depend too much on  $\beta$ .
- These methods consist in finding a change in the curvature of  $(K, J_K)$  :  $K$  is chosen so that  $J_K$  ceases to significantly decrease.

# Adaptive choice for the penalty parameter I

- Assume that the penalization  $\text{pen}(\tau)$  depends only on the dimension of the model, i.e., the number of segments  $K$ . Set

$$\begin{aligned}J_K &= J(\hat{\tau}_K, \mathbf{Y}), \\ \rho_K &= \text{pen}(\tau), \quad \forall \tau \in \mathcal{T}_K \\ \hat{\rho}_K &= \text{pen}(\hat{\tau}_K).\end{aligned}$$

- Thus, for any penalty parameter  $\beta > 0$ , the solution  $\hat{\tau}(\beta)$  minimize the penalized contrast:

$$\begin{aligned}\hat{\tau}(\beta) &= \arg \min_{\tau} (J(\tau, \mathbf{Y}) + \beta \text{pen}(\tau)) \\ &= \hat{\tau}_{\hat{K}(\beta)}\end{aligned}$$

where

$$\hat{K}(\beta) = \arg \min_{K \geq 1} \{J_K + \beta \rho_K\}.$$

# Adaptive choice for the penalty parameter II

- The solution  $\hat{K}(\beta)$  is a piecewise constant function of  $\beta$ . If  $\hat{K}(\beta) = K$ ,

$$J_K + \beta p_K < \min_{L \neq K} (J_L + \beta p_L).$$

- The,  $\beta$  verifies

$$\max_{L > K} \frac{J_K - J_L}{p_L - p_K} < \beta < \min_{L < K} \frac{J_L - J_K}{p_K - p_L}.$$

- Then, there exists a sequence  $\{K_1 = 1 < K_2 < \dots\}$ , and a sequence  $\{\beta_0 = \infty > \beta_1 > \dots\}$ , with

$$\beta_i = \frac{J_{K_i} - J_{K_{i+1}}}{p_{K_{i+1}} - p_{K_i}}, \quad i \geq 1,$$

such that  $\hat{K}(\beta) = K_i, \forall \beta \in [\beta_i, \beta_{i-1})$ .

- The set  $\{(p_{K_i}, J_{K_i}), i \geq 1\}$  is the convex envelope of the set  $\{(p_K, J_K), K \geq 1\}$ .

# Adaptive choice for the penalty parameter III

- The estimated sequence  $\hat{\tau}(\beta)$  should not depend too much on the choice for the penalty parameter  $\beta$  (a small variation of  $\beta$  should not yield a very different solution  $\hat{\tau}$ ).
- This stability of the solution with respect to the choice for  $\beta$  will be insured if we consider the largest intervals  $[\beta_i, \beta_{i-1}), i \geq 1$ .

We use the following procedure:

- 1 for  $K = 1, 2, \dots, K_{MAX}$ , compute  $\hat{\tau}_K$ ,  $J_K = J(\hat{\tau}_K, \mathbf{Y})$  and  $\hat{p}_K = \text{pen}(\hat{\tau}_K)$ ,
- 2 compute the sequence  $\{K_i\}$  and  $\{\beta_i\}$ , and the lengths  $\{l_{K_i}\}$  of the intervals  $[\beta_i, \beta_{i-1})$ ,
- 3 consider the highest value of  $K_i$  such that  $l_{K_i} \gg l_{K_j}$ , for  $j > i$ .

# Adaptive choice for the penalty parameter: heuristic approach I

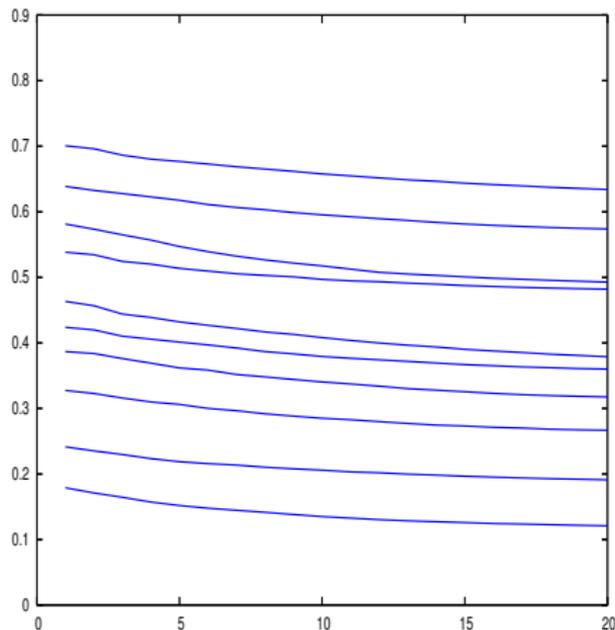
Graphical method for selecting the dimension  $K$  could be summarized as follows:

- 1 examine the decrease of the contrast  $J_K$  when  $K$  increases
  - 2 select  $K$  for which  $J_K$  ceases to significantly decrease.
- This amounts to look for the maximal curvature of  $(p_K, J_K)$ ,
  - Second derivative of that curve is linked to the length of the interval  $([\beta_i, \beta_{i-1}), i \geq 1)$ ,
  - Looking for a change in the decrease amounts to look for a change in the slope of the curve.

# Adaptive choice for the penalty parameter: heuristic approach II

- This requires a careful inspection of the curve, and is difficult to automatize.
- Consider an alternative approach more easy to automatize
- Principle of the method: model the decrease of the sequence of contrasts  $\{J_K\}$  when there is no change point in the series  $\{\mathbf{Y}_t\}$  and look for which value of  $K$  this model adjusts the  $\{J_K\}$
- No analytical solution for finding the distribution of the  $\{J_K\}$
- Some simulations show that this sequence decreases as  $c_1 K + c_2 K \log(K)$ .

# Adaptive choice for the penalty parameter: heuristic approach III



- Ten sequences of contrast function  $\{J_K\}$  computed from 10 sequences of Gaussian iid. random variable with coefficient of correlation  $\rho = 0.5$
- The fit to the function  $c_1 K + c_2 K \log(K)$  is almost perfect ( $r^2 > 0.999$ ). (estimated coefficients  $\hat{c}_1$  and  $\hat{c}_2$  are different for each of these series)

# Adaptive choice for the penalty parameter: heuristic approach IV

## Algorithm

For  $i = 1, 2, \dots$ ,

- 1 Fit the model:

$$J_K = c_1 K + c_2 K \log(K) + e_K,$$

to the series  $\{J_K, K \geq K_i\}$ , assuming that  $\{e_K\}$  is a sequence of Gaussian iid. and centered random variables.

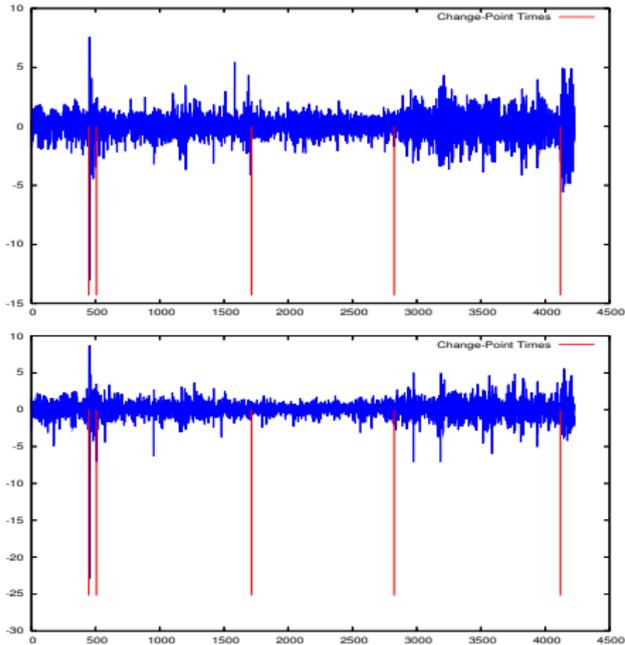
- 2 Evaluate the probability that  $J_{K_i-1}$  follows this model, i.e., the probability

$$\mathcal{P}_{K_i} = P(e_{K_i-1} \geq J_{K_i-1} - \hat{c}_1(K_i - 1) + \hat{c}_2(K_i - 1) \log(K_i - 1)),$$

under the estimated model.

- 3 The estimated number of segments is the highest value of  $K_i$  such that the  $P$ -value  $\mathcal{P}_{K_i}$  is lower than a threshold  $\alpha$ . (We set  $\alpha = 10^{-7}$  and  $K_{MAX} = 20$ )

# Application to the bivariate series of the FT100 and S&P 500 indices



- Adaptive detection of change-points in multivariate series
- Top: returns on FTSE 100
- Bottom: returns on S&P 500

- On multivariate GARCH processes, this method detects the change points with a great precision (with a greater precision than in the univariate case)
- This method provides better results than parametric tests extended to the multivariate case (e.g., the multivariate generalized likelihood ratio test)
- On real data, the automatic method detects the significant changes (stock market crashes)
- However, the user could tune the level of resolution by choosing the level of the  $P$ -value  $\mathcal{P}_{K_i}$ .

# Wavelet analysis for long-memory processes I

## Definition

Let  $\{Y_t, t \in \mathbb{R}\}$  be a second-order stationary process. This process is a long-memory process if its spectrum  $f_Y(\lambda)$  is such that in a close positive neighborhood of the zero frequency,

$$f_Y(\lambda) \sim c_f \lambda^{-\alpha}, \quad \lambda \rightarrow 0_+, \quad c_f \in (0, \infty),$$

or equivalently, if its autocorrelation function  $\rho_Y(k)$  has the following hyperbolic rate of decay<sup>a</sup>

$$\rho_Y(k) \asymp k^{\alpha-1},$$

with  $\alpha \in (0, 1)$ .

---

<sup>a</sup> $x_k \asymp y_k$  means that  $\exists$  two constants  $C_1, C_2$  such that  $C_1 y_k \leq x_k \leq C_2 y_k, k \rightarrow \infty$ .

# Wavelet analysis for long-memory processes II

- Statistical tools based on global statistics are not robust to trends, breaks, etc,
- We then consider an alternative statistical method more robust to these nonlinearities,
- Wavelets based methods are robust to trend, change-points and nonlinearities
- So that they allow us to adjudicate between long-range dependence, non-stationarities, nonlinearities, change-points (Teyssiere and Abry, 2005).

# Wavelet estimator of $d$

- The mother wavelet  $\psi_0$  has  $\mathcal{N}$  moments of order zero, with  $\mathcal{N} \geq 1$ , i.e.,

$$\int t^k \psi_0(t) dt \equiv 0, \quad k = 0, \dots, \mathcal{N} - 1.$$

- $\psi_{j,k}$  is a family of waveforms  $\{\psi_{j,k} = 2^{-j/2} \psi_0(2^{-j}t - k)\}$ , i.e., a collection of dilations and translations of the mother wavelet  $\psi_0$
- $j = 1, \dots, J$  are the octaves,  $k \in \mathbb{Z}$
- Discrete wavelet coefficients are defined by:  $d_X(j, k) = \int_{\mathbb{R}} X(t) \psi_{j,k}(t) dt$
- Veitch and Abry (1999) estimator of  $\alpha = 2d$ , based on the DWT and the properties of independence of wavelet coefficients  $d_X(j, k)$  of Gaussian fractional processes.

# Daubechies wavelets

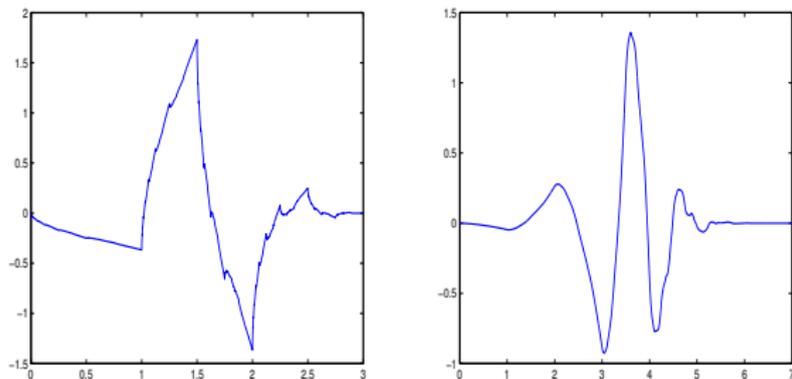


Figure: Daubechies 2 (left) and Daubechies 4 (right)

- We use here Daubechies wavelets,
- Daubechies wavelets have a support of minimum size for a given number of  $\mathcal{N}$  vanishing moments.

# Moments of order zero of a wavelet

- The moments of order zero  $\mathcal{N}$  is a key variable for wavelet analysis.

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- We choose  $\mathcal{N}$  for obtaining an estimate of the long-memory parameter which cannot be affected by trends and non-stationarities.

# Example of strongly dependent time series with a trend

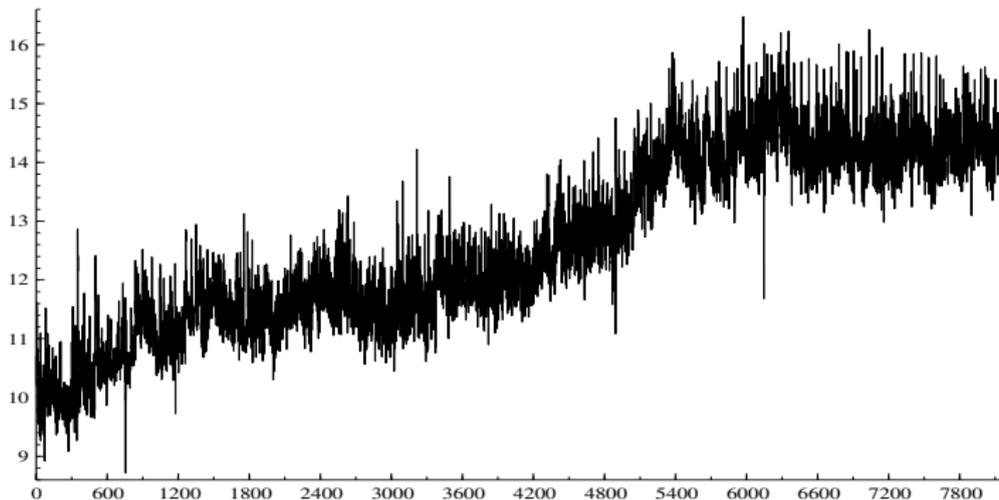


Figure: Logarithm of the volume of transactions on AT&T

# Estimation of $d$

- The process  $d_X(j, k)$  is stationary (if  $\mathcal{N} \geq (\alpha - 1)/2$ )
- For the largest octaves, its variance satisfies the following power law:

$$Ed_X(j, \cdot)^2 = 2^{j\alpha} c_f C, \quad \text{as } 2^j \rightarrow \infty, \quad C = \int |\lambda|^{-\alpha} |\Psi_0(\lambda)|^2 d\lambda,$$

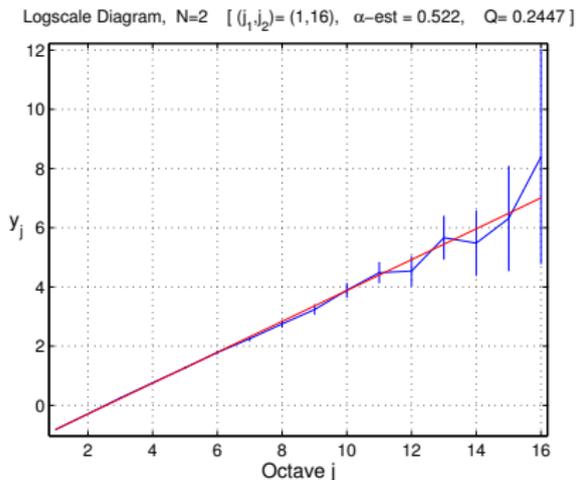
( $\Psi_0(\lambda)$  is the Fourier transform of the mother wavelet  $\psi_0$ .)

- The scaling parameter  $\alpha$  is estimated from the slope of the following linear regression:

$$\log_2 (Ed_X(j, \cdot)^2) = j\alpha + \log_2(c_f C) \quad \text{called "logscale diagram"}$$

- Estimation of this regression by weighted least squares

# Example of a logscale diagram



- “Logscale diagram” of a fractional Gaussian noise,  $d = 0.25$
- $\hat{\alpha} = 2\hat{d} = 0.522$
- We could select all octaves as the scaling law appears from the first octave.
- As we will see later, for nonlinear LRD processes the first octaves are affected by the presence of nonlinearities
- For nonlinear LRD processes, the scaling law clearly appears in the largest octaves.

# Asymptotic distribution of the estimator

- Define:  $S_X(j) = \frac{1}{n_j} \sum_{k=1}^{n_j} d_X(j, k)^2$

$n_j$ : number of wavelet coefficients  $d_X(j, k)$  available at octave  $j$ ,  $n_j = O(2^{-j} T)$

- Wavelet estimator (for the range of octaves  $[j_1, j_2]$ )

$$\hat{\alpha}_W = \sum_{j=j_1}^{j_2} w_j (\log_2 S_X(j) - (\psi(n_j/2)/\log 2 - \log_2(n_j/2)))$$

$$w_j = \frac{1}{a_j} \frac{S_{0j} - S_1}{S_0 S_2 - S_1^2}, \quad S_p = \sum_{j=j_1}^{j_2} j^p / a_j, \quad a_j = \zeta(2, n_j/2)$$

- This estimator has “approximately” the following asymptotic distribution:

$$(\hat{\alpha} - \alpha) \sim N\left(0, \frac{1}{T \ln^2(2) 2^{1-j_1}}\right),$$

- $j_1$  is the lowest octave, the long range behavior is captured by the octaves greater than  $j_1$ .

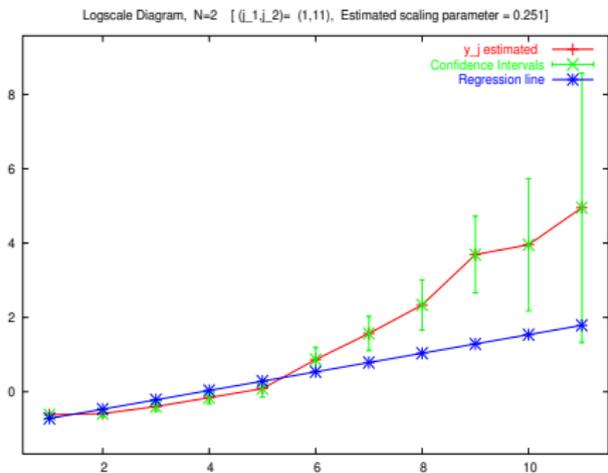
# How to select the lowest octave $j_1$ ?

- If  $j_1$  is too small : strong bias as the interval contains some octave that do not verify the scaling law, but only short term dependencies and non-linearities.
- If  $j_1$  is too “large” : bias is reduced but the variance becomes large
- Selection of  $j_1$  in relation with the problem of optimal bandwidth selection for the local Whittle estimator in the frequency domain
- The octave associated with the optimal bandwidth  $m_{LW}^{opt}$  of the local Whittle estimator is then equal to  $m_{LW}^{opt}/T$ , and matches the octave  $2^{-j_1}$ .
- Using  $m_{LW}^{opt}$  we define the optimal lower octave :

$$j_1^{opt} = \left\lceil \frac{\log T - \log m_{LW}^{opt}}{\log 2} \right\rceil,$$

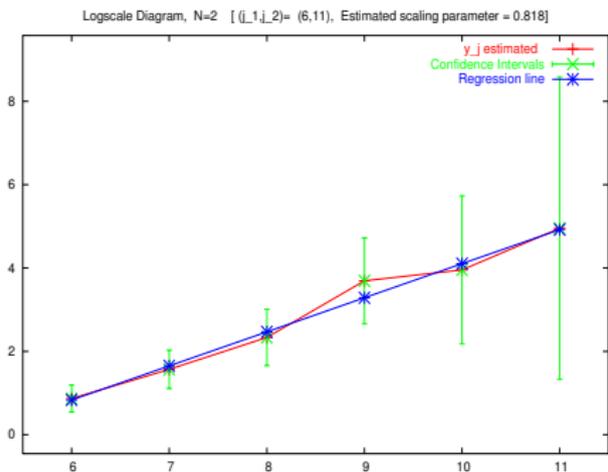
- This gives satisfactory results. (So far, there is no alternative method)

# Example: selecting $j_1$ for nonlinear models I



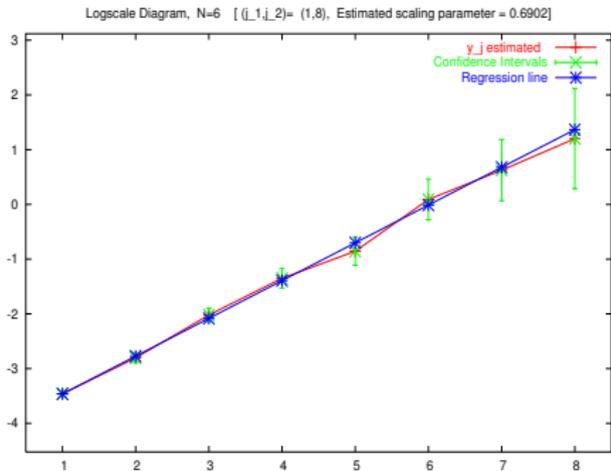
- “Logscale diagram” of a long-memory stochastic volatility model (LMSV) with  $\alpha = 2d = 0.90$
- $\hat{\alpha} = 2\hat{d} = 0.25$ ,
- $\hat{\alpha} \ll \alpha$  as we wrongly select all octaves while the scaling law does not appear in the first octaves,
- The scaling law appears in the largest octaves,
- The first octaves are affected by the short-range nonlinearities of the LMSV.

# Example: selecting $j_1$ for nonlinear models II



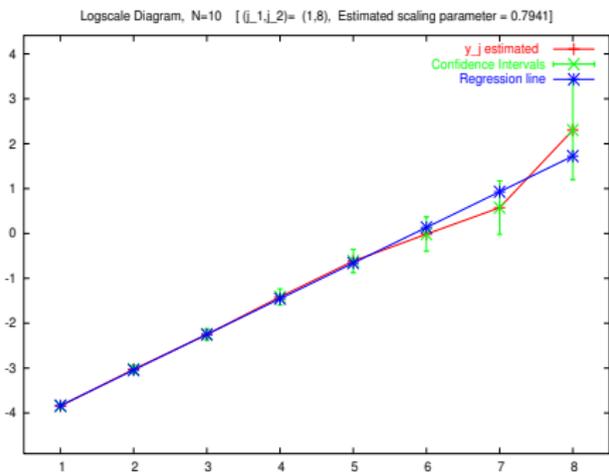
- “Logscale diagram” of a long-memory stochastic volatility model (LMSV)  $\alpha = 2d = 0.90$
- $\hat{\alpha} = 2\hat{d} = 0.818$
- We set  $j_1 = 6$  as the scaling law appears after that octave.
- Same issue is present for other nonlinear LRD processes; See Teysnière and Abry (2005) for further details.

# Volume of transactions: how to select $\mathcal{N}$ ? I



- Logscale diagram for the log-volume of transactions on AT&T shares ,  $j_1 = 1$ ,  $\mathcal{N} = 6$ ;  $\hat{\alpha} = 0.6902$
- We select  $\mathcal{N} = 6$  because of the trend (estimation results are stable for  $\mathcal{N} \geq 6$ )
- We select all octaves as the scaling law appears from the first octave.

# Volume of transactions: how to select $\mathcal{N}$ ? II

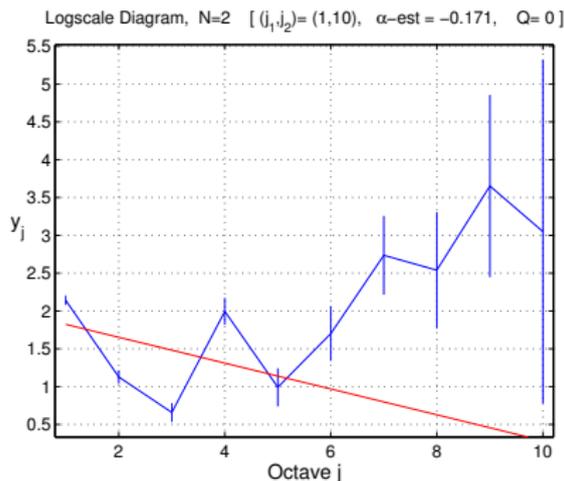


- Logscale diagram for the log-volume of transactions on IBM shares ,  $j_1 = 1, \mathcal{N} = 10; \hat{\alpha} = 2\hat{d} = 0.7941$
- We select  $\mathcal{N} = 10$  because of the trend (estimation results are stable for  $\mathcal{N} \geq 10$ )
- We select all octaves as the scaling law appears from the first octave.

# Are volume and volatility sharing the same long-memory properties ?

- Previous works on the common long-memory properties of prices and volume
- Both processes are supposed to inherit their long-memory properties from a news arrival process (the so-called mixture of distribution hypothesis, MDH)
- We apply the wavelet estimator to the same series used by Lobato and Velasco (2000).

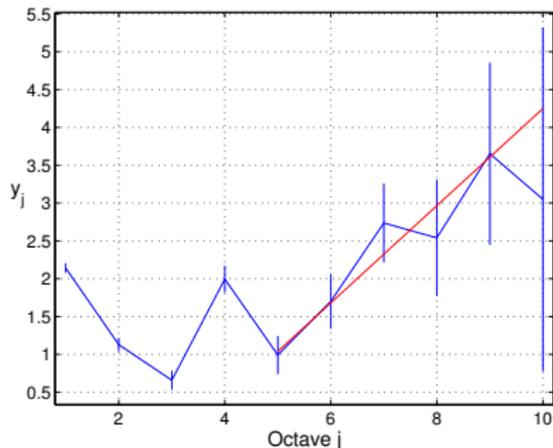
# Logscale diagrams for volatility series I



- Logscale diagram for the absolute returns on AT&T shares,  $j_1 = 1$ ,  $\mathcal{N} = 2$ ;  $\hat{\alpha} = 2\hat{d} = -0.171$
- It is obvious that the scaling law does not appear from the first octave
- The volatility process is less “nice” than the volume process.

# Logscale diagrams for volatility series II

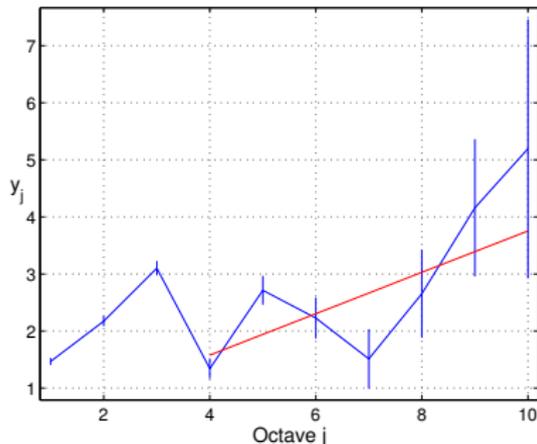
Logscale Diagram, N=2 [  $(j_1, j_2) = (5, 10)$ ,  $\alpha$ -est = 0.642,  $Q = 0.30528$  ]



- Logscale diagram for the absolute returns on AT&T shares,  $j_1 = 5$ ,  $\mathcal{N} = 2$ ;  $\hat{\alpha} = 2\hat{d} = 0.642$
- Volume and volatility processes appear to have different scaling properties. (See Teysnière and Abry (2005) for further details).

# Logscale diagrams for volatility series III

Logscale Diagram,  $N=2$  [ $(j_1, j_2) = (4, 10)$ ,  $\alpha$ -est = 0.363,  $Q = 7.0721e-13$ ]



- Logscale diagram for the absolute returns on IBM shares,  $j_1 = 4$ ,  $\mathcal{N} = 2$ ;  $\hat{\alpha} = 2\hat{d} = 0.363$
- Volume and volatility processes appear to have different scaling properties.
- Volatility series appear to have a lower degree of long-memory than was usually claimed using other non robusts estimators. (See Teysnière and Abry (2005) for other examples).

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